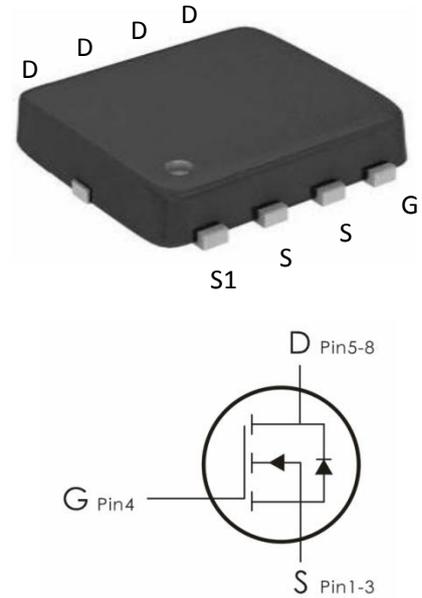


Description:

This N-Channel MOSFET uses advanced trench technology to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

Features:

- 1) $V_{DS}=100V, I_D=10A, R_{DS(ON)} < 125m\Omega @ V_{GS}=10V$
- 2) Improved dv/dt capability
- 3) Fast switching
- 4) 100% EAS Guaranteed
- 5) Green Device Available.



Absolute Maximum Ratings: ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Ratings	Units
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Continuous Drain Current-Continuous- $T_c=25^\circ C$	10	A
	Continuous Drain Current-Continuous- $T_c=100^\circ C$	6.5	A
I_{DM}	Drain Current – Pulsed ¹	40	A
EAS	Single Pulse Avalanche Energy ²	3.8	mJ
P_D	Power Dissipation - $T_c=25^\circ C$	20	W
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150	$^\circ C$

Thermal Characteristics:

Symbol	Parameter	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	6.3	$^\circ C/W$

Package Marking and Ordering Information:

Part NO.	Marking	Package
ZH130NG	H130N	DFN3*3-8

Electrical Characteristics: ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\ \mu\text{A}$	100	---	---	V
I_{DSS}	Drain-Source Leakage Current	$V_{GS}=0V, V_{DS}=100V$	---	---	1	μA
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0A$	---	---	± 100	nA
On Characteristics						
$V_{GS(th)}$	GATE-Source Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\ \mu\text{A}$	1	1.5	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance ³	$V_{GS}=10V, I_D=5A$	---	92	125	m Ω
		$V_{GS}=4.5V, I_D=3A$	---	98	137	
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=25V, V_{GS}=0V, f=1\text{MHz}$	---	811	---	pF
C_{oss}	Output Capacitance		---	50	---	
C_{rss}	Reverse Transfer Capacitance		---	35	---	
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}=50V, V_{GS}=10V,$ $R_G=1.8\ \Omega, I_D=3A$	---	7	---	ns
t_r	Rise Time		---	5	---	ns
$t_{d(off)}$	Turn-Off Delay Time		---	16	---	ns
t_f	Fall Time		---	6	---	ns
Q_g	Total Gate Charge	$V_{DS}=50V, V_{GS}=10V, I_D=2A$	---	12	---	nC
Q_{gs}	Gate-Source Charge		---	2.2	---	nC
Q_{gd}	Gate-Drain "Miller" Charge		---	2.5	---	nC
Drain-Source Diode Characteristics						
I_S	Continuous Source Current	$V_G=V_D=0V$	---	---	10	A
V_{SD}	Forward on voltage	$I_S=10A, V_{GS}=0V$	---	---	1.2	V

Trr	Body Diode Reverse Recovery Time	IF=3A, di/dt=100A/μs	---	21	---	nS
			---	21	---	nC
Qrr	Body Diode Reverse Recovery Charge					

Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition: $T_J=25^\circ\text{C}$, $V_{DD}=30\text{V}$, $V_G=10\text{V}$, $L=0.5\text{mH}$, $R_G=25\Omega$, $I_{AS}=3.9\text{A}$
3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$

Typical Characteristics: ($T_C=25^\circ\text{C}$ unless otherwise noted)

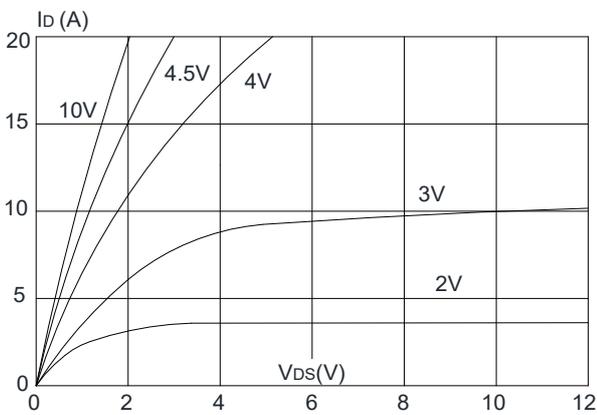


Figure 1: Output Characteristics

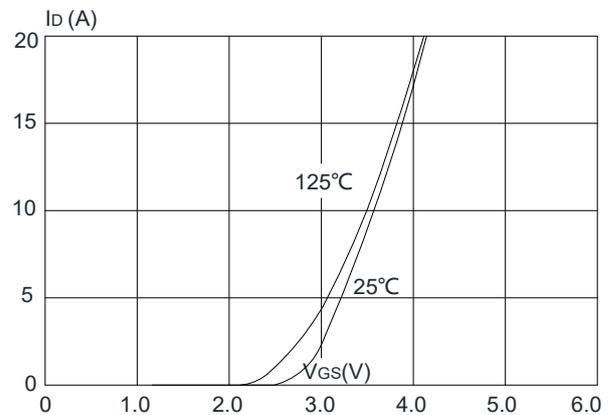


Figure 2: Typical Transfer Characteristics

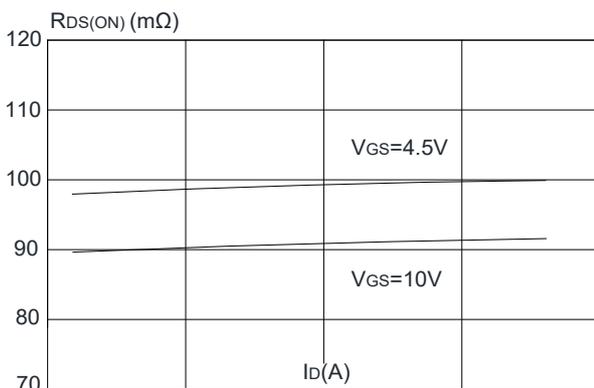


Figure 3: On-resistance vs. Drain Current

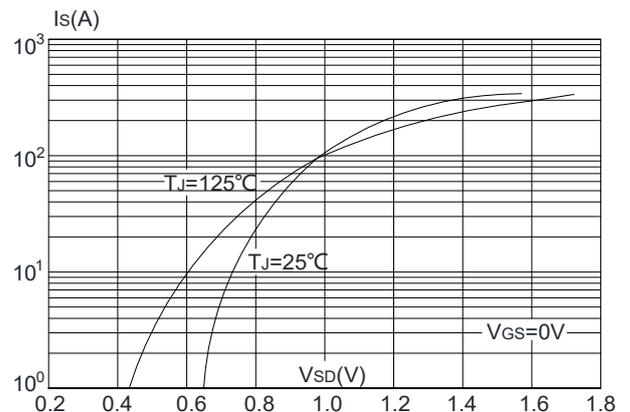


Figure 4: Body Diode Characteristics

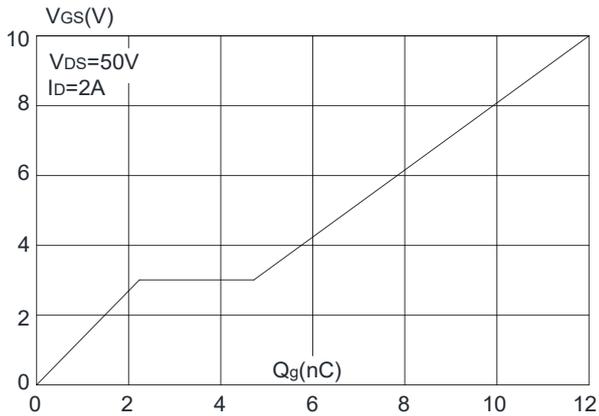


Figure 5: Gate Charge Characteristics

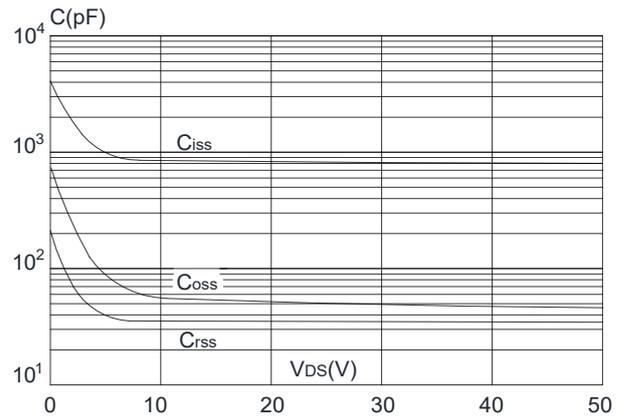


Figure 6: Capacitance Characteristics

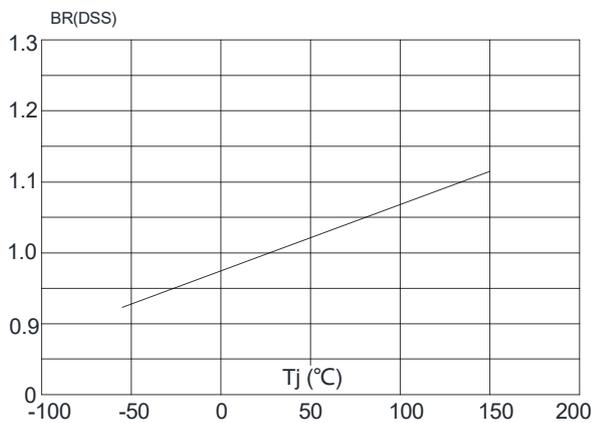


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

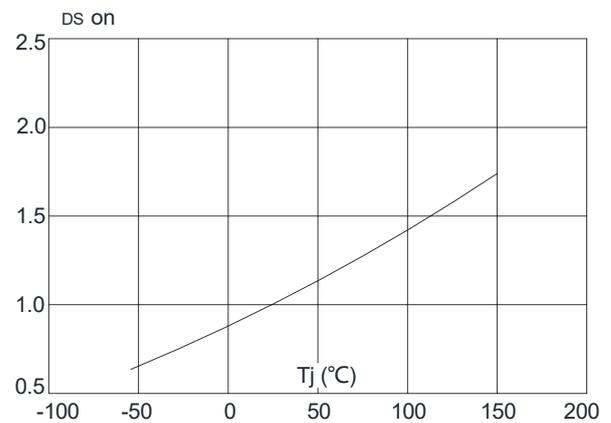


Figure 8: Normalized on Resistance vs. Junction Temperature

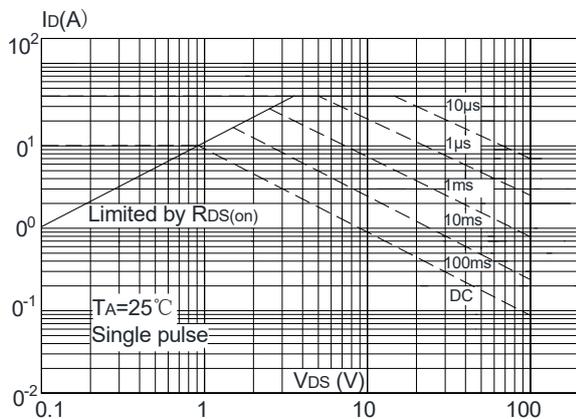


Figure 9: Maximum Safe Operating Area

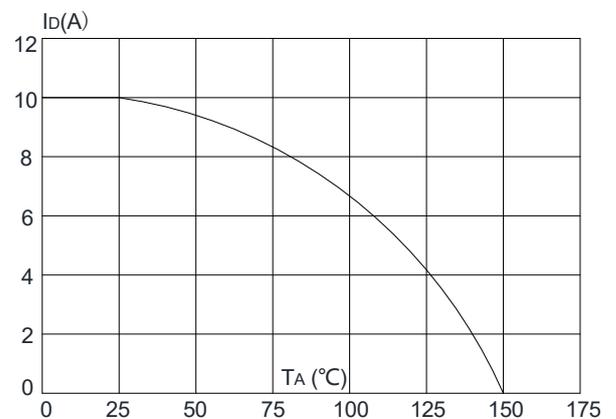


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

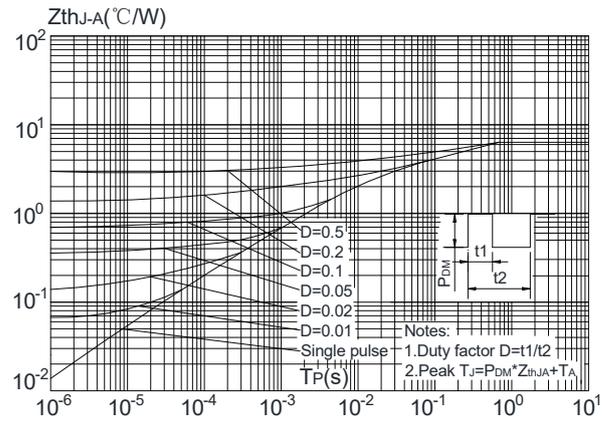


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient